

A Nyquist Rate Pixel Level ADC for CMOS Image Sensors

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Outline

- Motivation and background
- Our ADC Operation
- Implementation

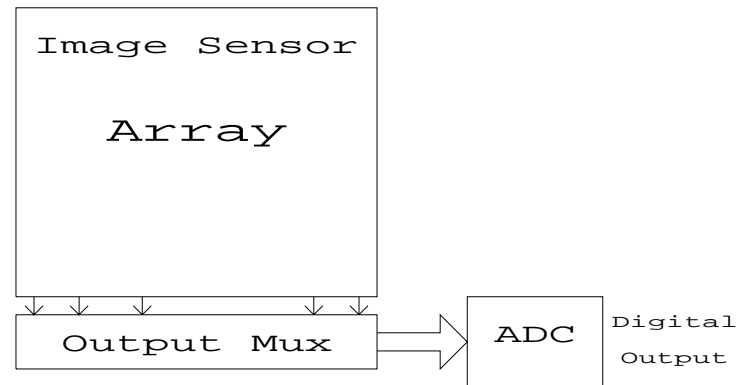
Motivation

Single chip CMOS digital camera

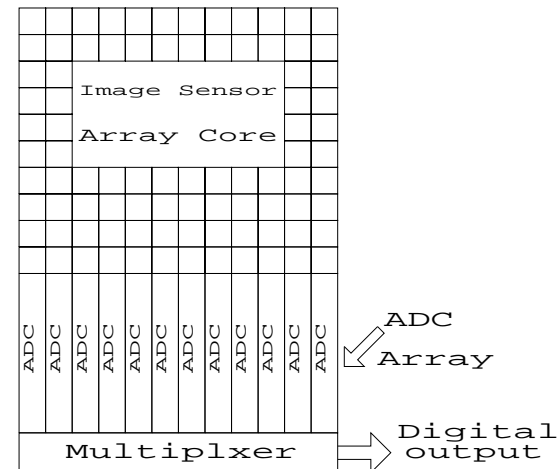
- Image sensor array (e.g. APS)
- ADC
- Image processing and compression
- Control
- Memory

Approaches to ADC Integration

- Chip Level



- Column Level



Pixel Level ADC

- ADC close to signal generation always better
 - highest SNR
 - lowest power
- Scalable sensor architecture
- Process portability – compatible with digital CMOS
- But
 - Very limited silicon area $\approx 10\mu m \times 10\mu m$

Constraints of Pixel Level ADC

- Cannot use bit-parallel ADCs
 - bit-serial is the way to go
- Cannot use conventional Nyquist rate bit-serial ADCs (e.g. SA, algorithmic).
 - simple and robust circuits are a must

Pixel Level Sigma Delta ADC

ISSCC 94, CICC 96

- 1-bit first order $\Sigma\Delta$ ADC per pixel or per four pixels, operating simultaneously
- Simple imprecise circuits can be used

Limitations of Sigma Delta ADC

- Poor low light response
- Moderate fixed pattern noise
- High output data rate - need decimation

Multi-channel bit-serial (MCBS) ADC

- Reduces output data rate
- Improves low light response
- Lowers fixed pattern noise
- Provides programmable step size quantization
- Provides in pixel testability

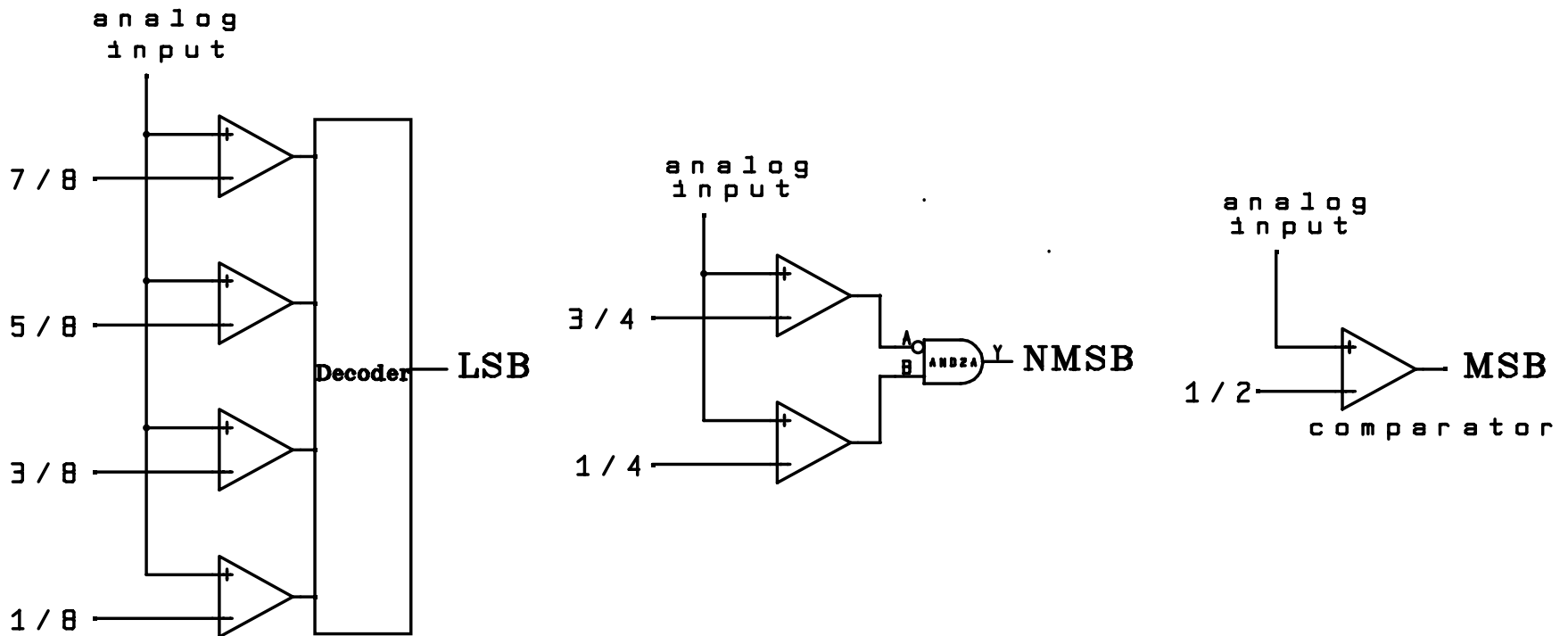
MCBS ADC Method

ADC implements a quantization table

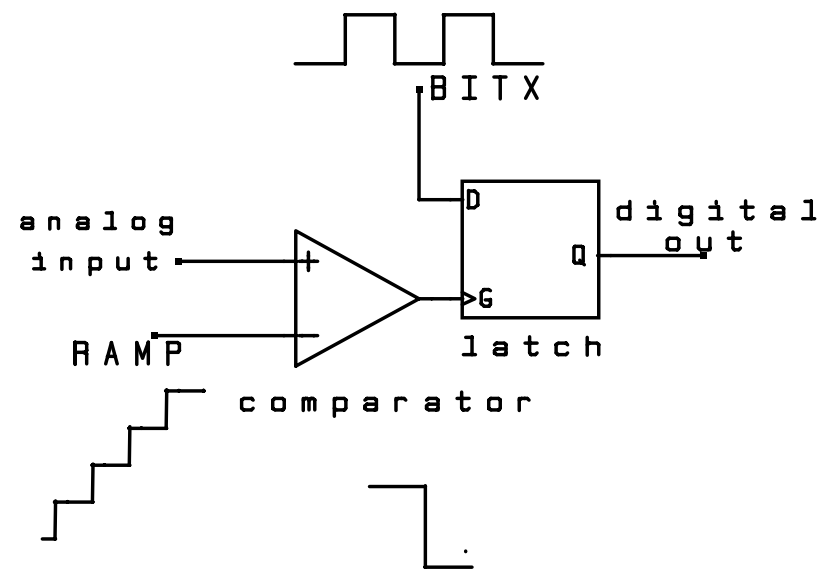
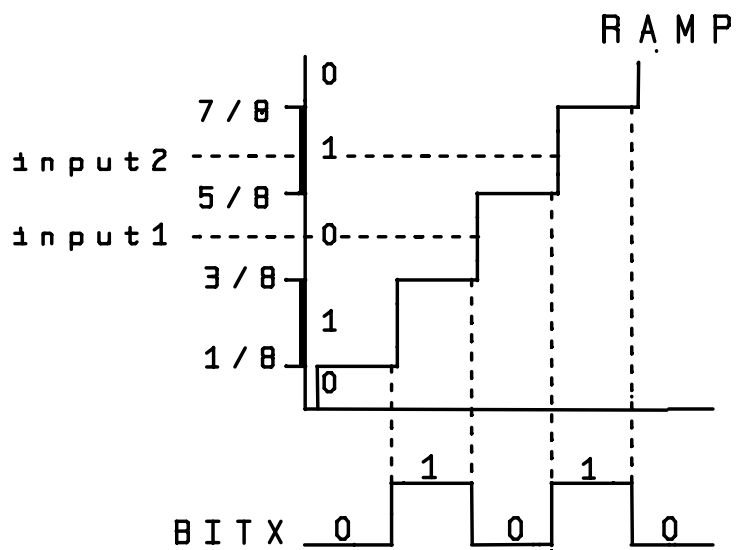
Quantization table	
ADC Input	Gray Code
S	
0 — $\frac{1}{8}$	0 0 0
$\frac{1}{8}$ — $\frac{2}{8}$	0 0 1
$\frac{2}{8}$ — $\frac{3}{8}$	0 1 1
$\frac{3}{8}$ — $\frac{4}{8}$	0 1 0
$\frac{4}{8}$ — $\frac{5}{8}$	1 1 0
$\frac{5}{8}$ — $\frac{6}{8}$	1 1 1
$\frac{6}{8}$ — $\frac{7}{8}$	1 0 1
$\frac{7}{8}$ — 1	1 0 0

Key Point: Each output bit is a binary-valued function (independent of other bits)

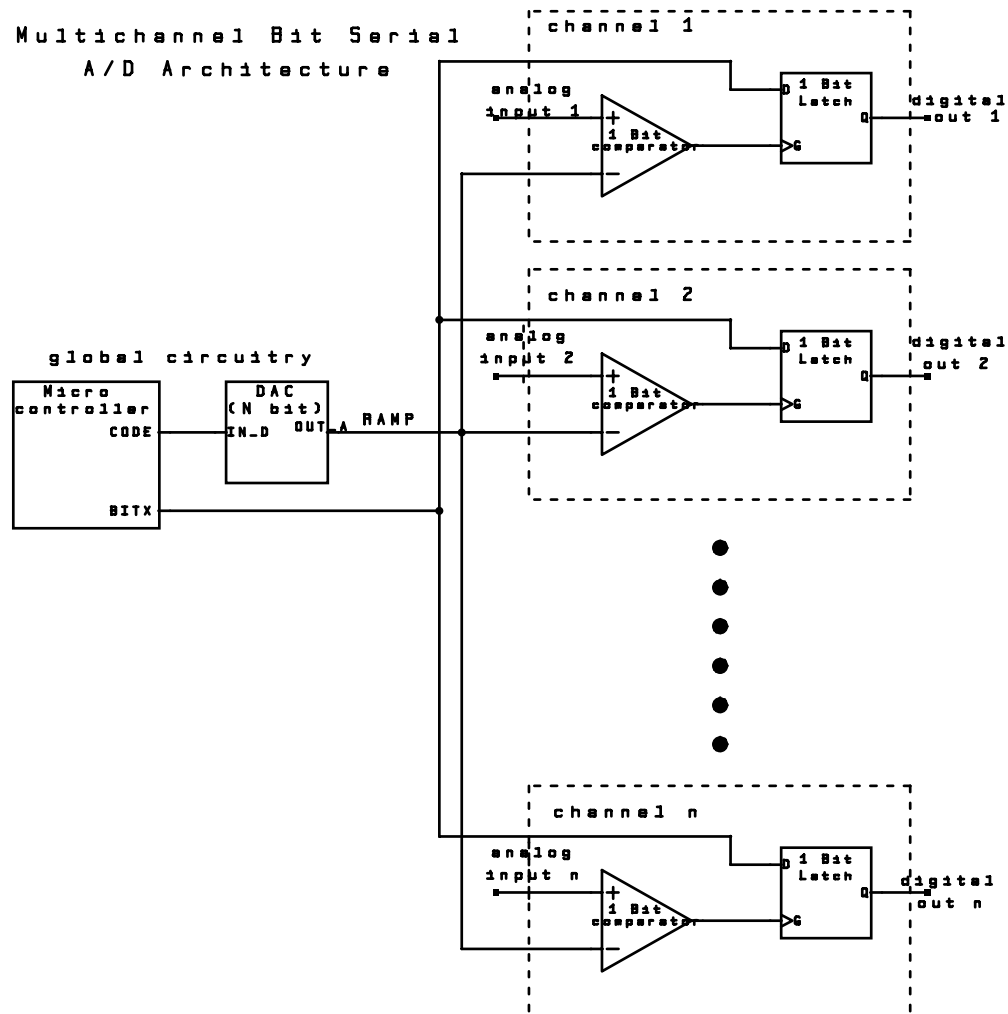
Flash ADC (Not MCBS ADC)



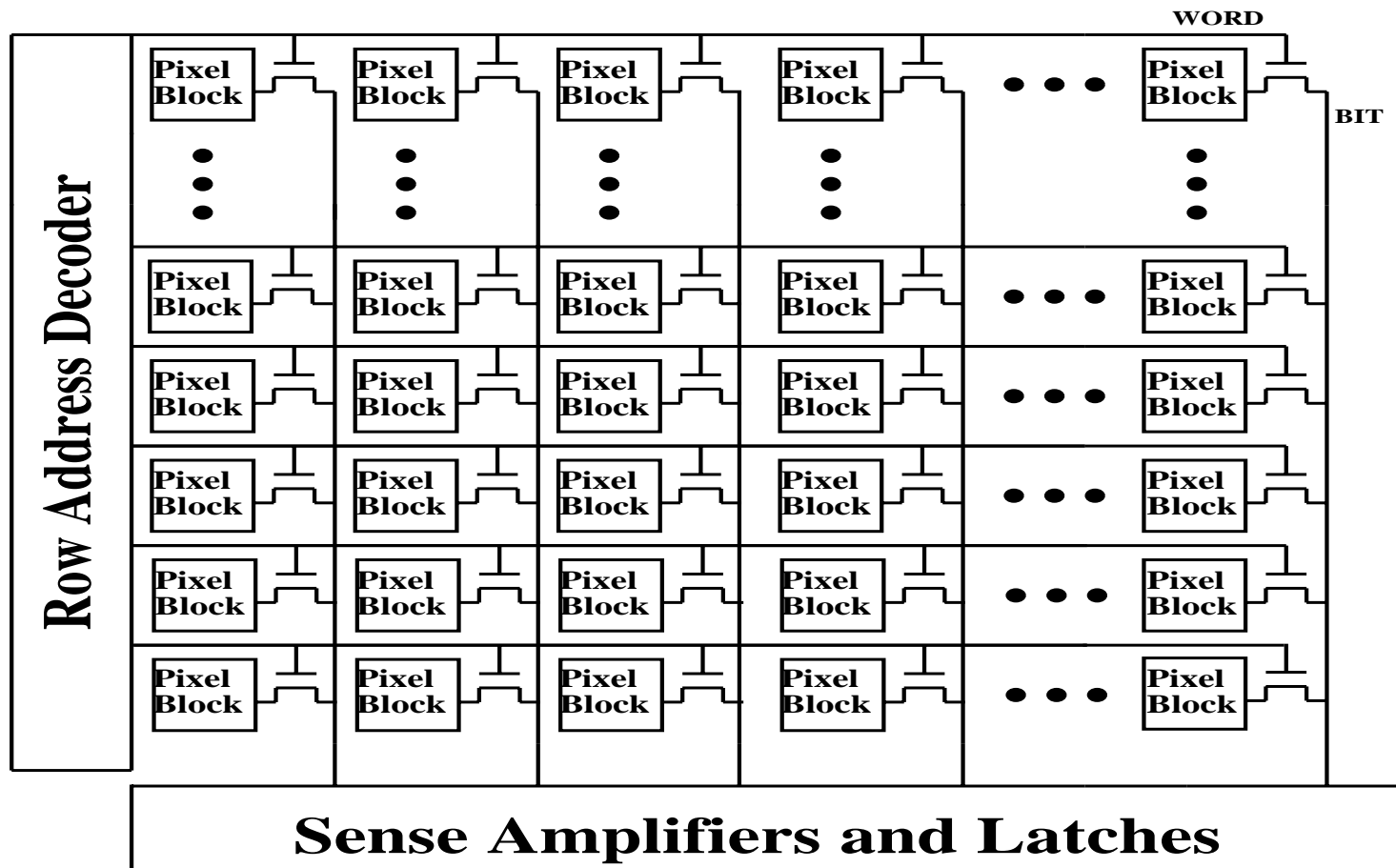
How 1-bit Comparator/Latch Works



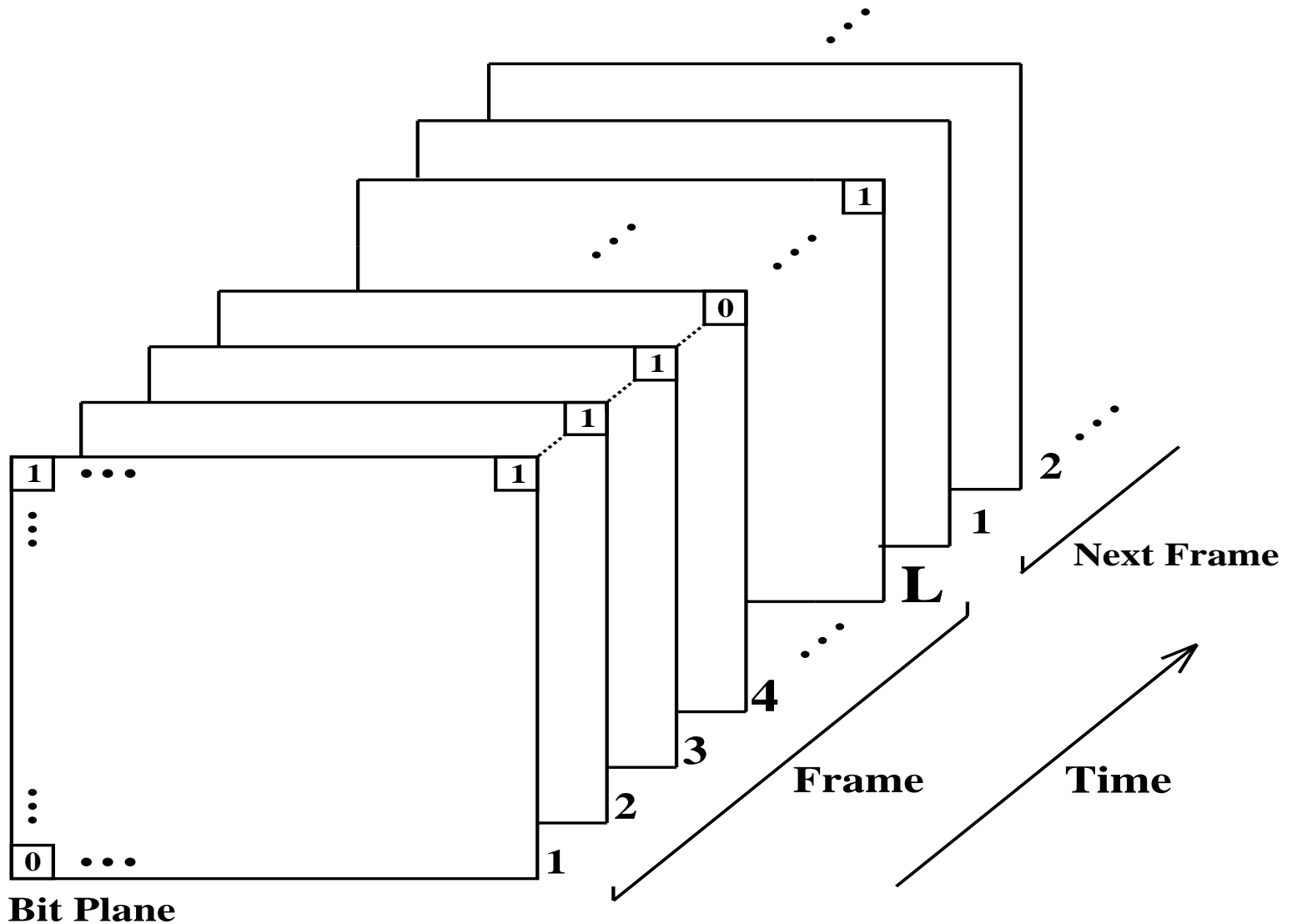
MCBS ADC – Block Diagram



Block Diagram for Image Sensor with Pixel Level ADC

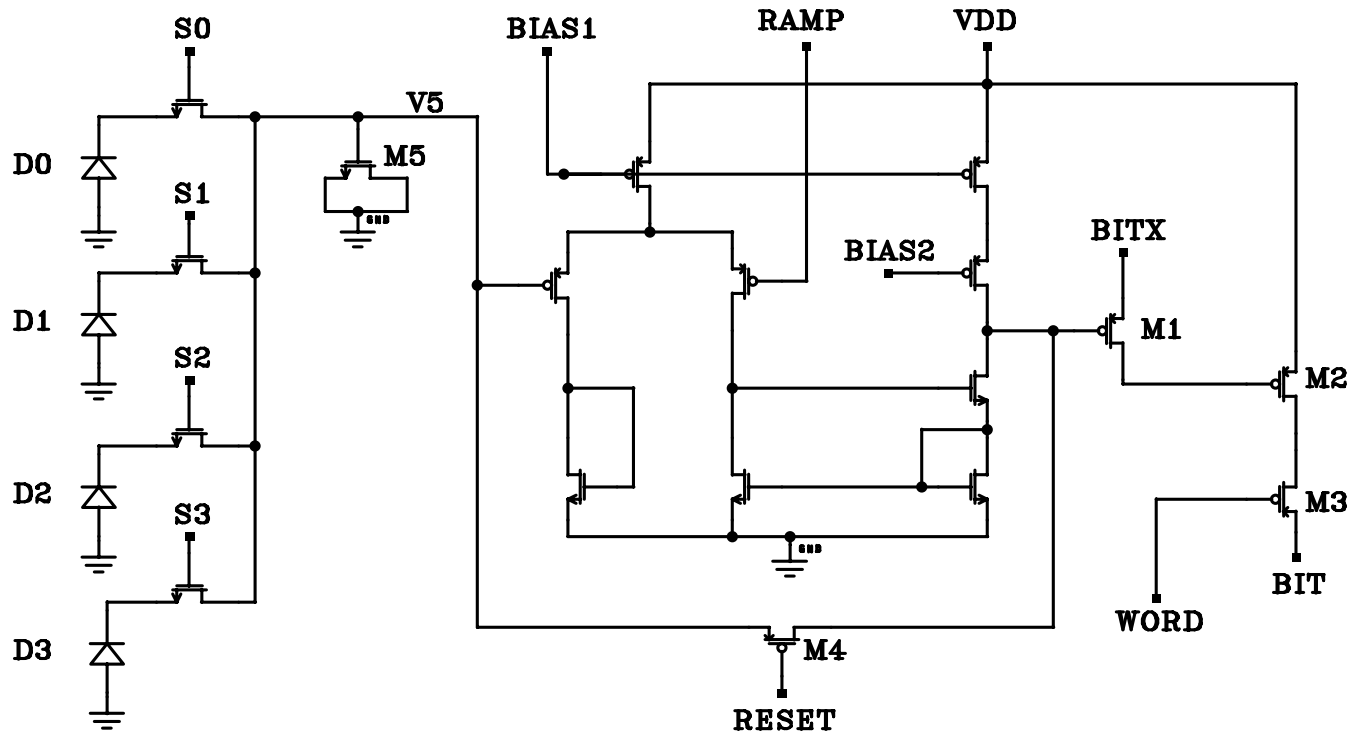


Output of Image Sensor with Pixel Level ADC

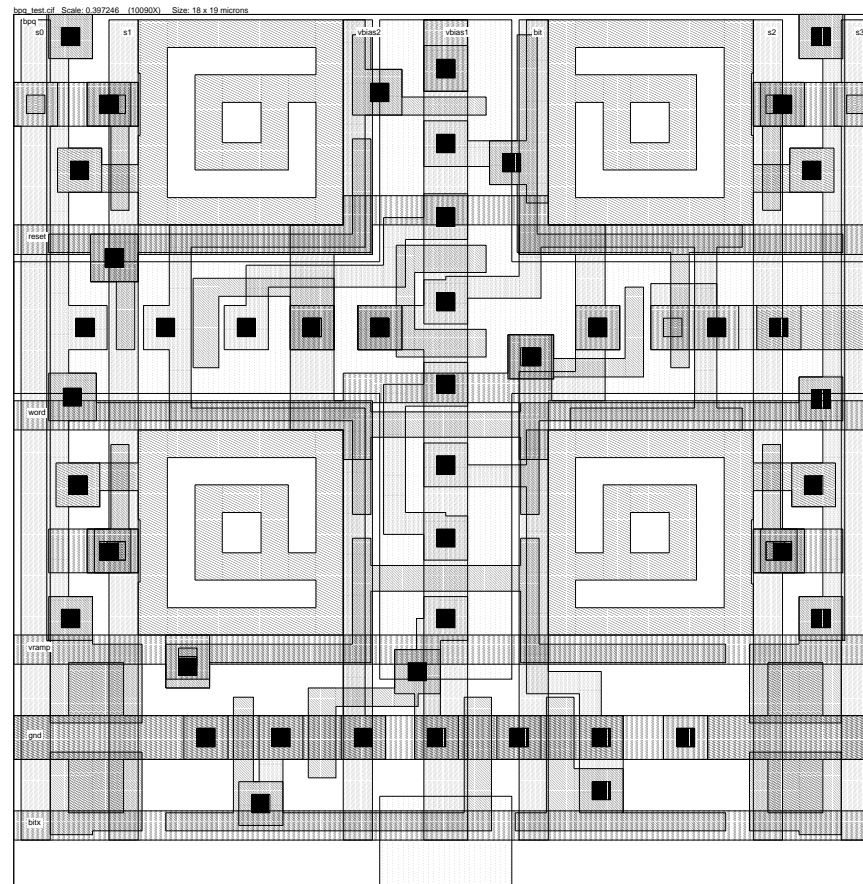


MCBS ADC Pixel Block Circuit Schematic - 18

Transistors



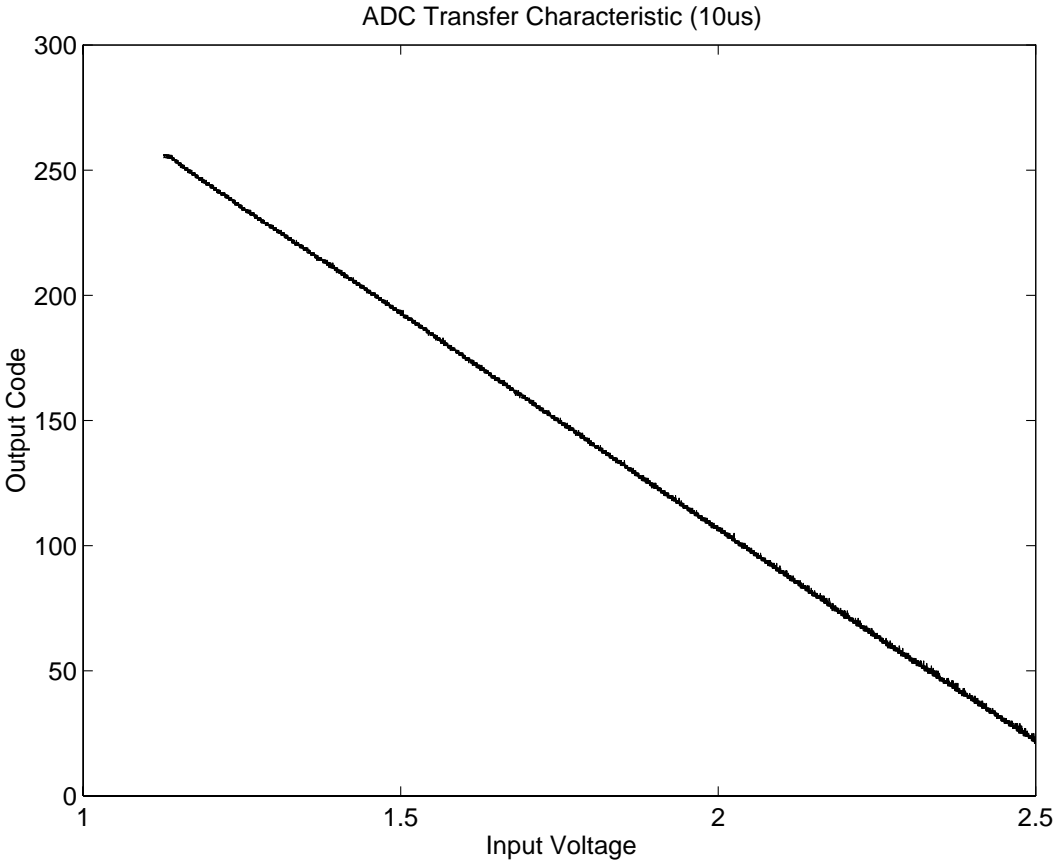
Nyquist Rate ADC Pixel Block Layout - $0.35\mu\text{m}$, $8.9\mu\text{m} \times 8.9\mu\text{m}$



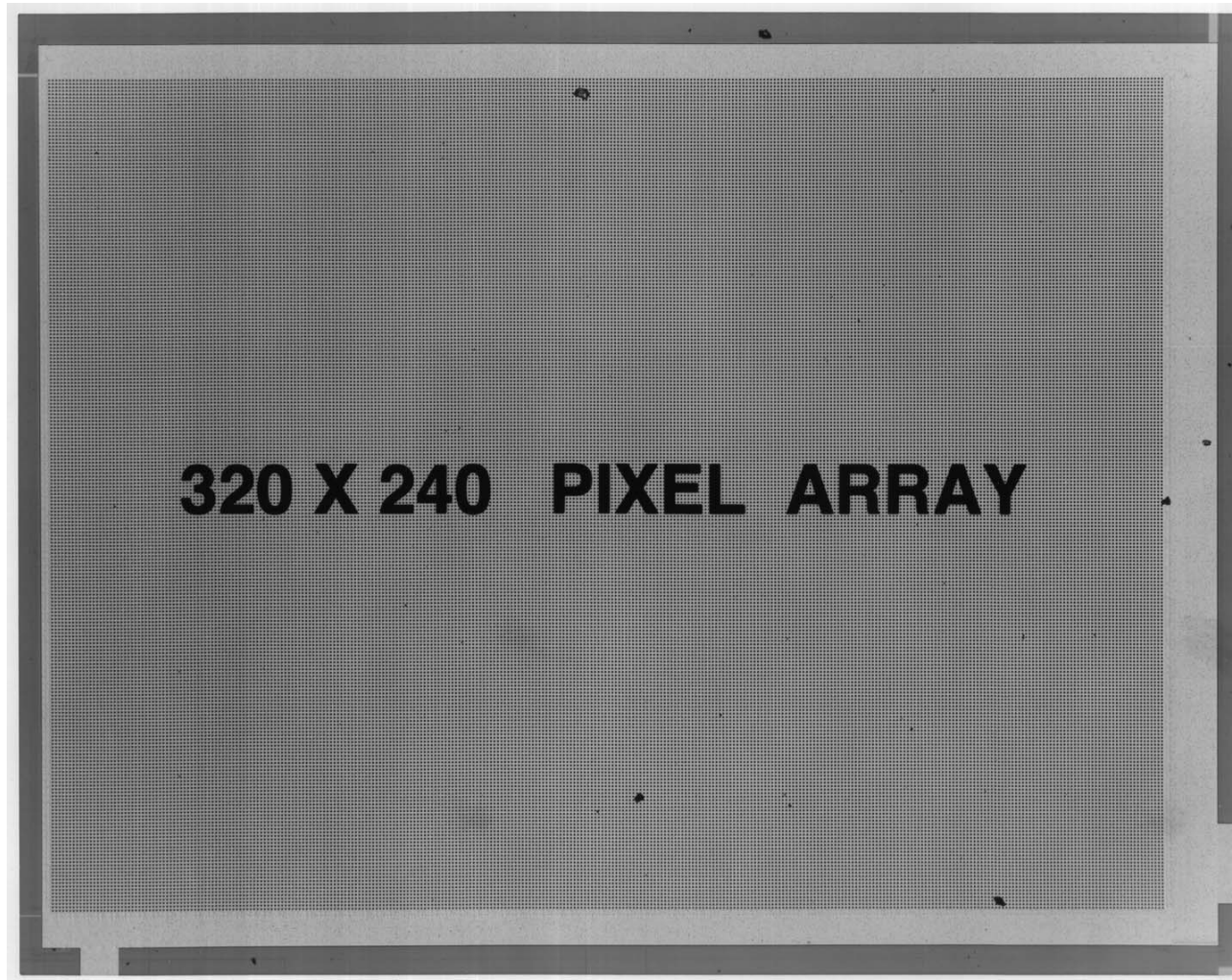
Main image sensor characteristics

Technology	0.35 μm , 4-layer metal, 1-layer poly, nwell CMOS
Sensor Area	3027 μm \times 2328 μm
Sensor size	320 \times 240 pixels
Pixel Area	8.9 μm \times 8.9 μm
Number of transistors per pixel	4.5 (18 per four pixels)
Fill Factor	25%
Package	224 pin PGA
Supply Voltage	3.3 V

Measured ADC Transfer Function



Die micrograph of 320×240 image sensor



Conclusion

- First Nyquist rate pixel level ADC technique
 - Simple circuits
 - Very low power
 - Electrically testable
- A CMOS image sensor in a 0.35 μm 4 metal layer digital process
 - $8.9 \times 8.9 \mu\text{m}$
 - 25% fill factor